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First AXIe® 3.1 Standard System Module

HOPKINTON, MA—October 27, 2010—[Test Evolution Inc.](http://www.testevolution.com), the leading supplier of OEM test products based on the AXIe 3.1 open standard, announces its System Module as part of the Evolution® series of test systems focused on the semiconductor test market. The new System Module brings to the semiconductor industry one of the building blocks of an open hardware and software platform for both device characterization and production test, using common instruments and test programs for lower cost and faster time to volume production.

"The AXIe standard enables high performance instrumentation in an open standard modular solution. This will enable a renaissance in low cost focused test solutions in semiconductor test applications," said Lev Alperovich, president, Test Evolution. "The System Module is the first in a series of products that will give customers the tools to improve productivity, time to market, and ultimately better profitability."

The System Module is a single slot AXIe 3.1-compliant board. The System Module supports all functionality of AXIe 3.1 standard including robust backplane and front-panel triggering for inter-instrument control, 250 MB/s PCI Express to all slots, in-system calibration support, and controllable load board power supplies. The System Module, with its rear transition connector provides for cable-less connections to semiconductor devices in both characterization and production testing.

"The AXIe 3.1 triggering capabilities allow for Pattern Based Synchronization techniques leading to better test repeatability and fast test times," said David Oka, VP Engineering, Test Evolution. "The routing of test signals through the backplane and rear transition modules provides for cable free test fixtures, a major benefit for test repeatability." The System Module is compatible with National Instrument's LabVIEW® and TestStand®, and the IVI® software standard which are all widely used for device characterization, and easily coexists with PXI® and LXI® instruments and chassis. This capability allows for ATE

instruments to be used for characterization, and later the same instruments and test programs can be used in production, for both a cost and time savings for semiconductor device vendors.

Price and availability

The System Module is available now. For more information on pricing for the System Module or other products, contact David Oka at 508-377-5757 or email oka@testevolution.com.

About AXIe

AXIe is a standard based on AdvancedTCA[®] with extensions for instrumentation and test. The mission of the AXIe Consortium is to provide an open standard that creates a robust ecosystem of components, products and systems for general-purpose instrumentation and semiconductor test. AXIe leverages existing standards from PXI, LXI and IVI. AXIe promises high scalability and performance that will address a range of platforms including bench top measurements, rack-and-stack modular, and ATE systems. www.axiestandard.org

About Test Evolution

With expertise in digital, mixed-signal, and RF instrumentation, Test Evolution is offering a unique way of developing OEM ATE technology, providing the engineering expertise to develop test instruments, sub-systems and systems in an open standard format for ATE providers, system integrators, semi-test houses and silicon vendors. Test Evolution is a founding member of the AXIe Consortium. Information about Test Evolution is available on the Web at www.testevolution.com.

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